CLAIMS

[1] A projection optical system for forming a reduced image of a first surface onto a second surface:

a first reflective imaging optical system for forming an intermediate image of the first surface and a second reflective imaging optical system for forming an image of the intermediate image onto the second surface;

the first reflective imaging optical system including a concave first reflector, a concave second reflector equipped with an aperture stop, a convex third reflector, and a concave fourth reflector successively as light enters from the first surface side;

the second reflective imaging optical system including a concave fifth reflector, a concave sixth reflector, a convex seventh reflector, and a concave eighth reflector successively as light enters from the first surface side.

- [2] The projection optical system according to claim 1, wherein the fourth reflector is arranged in a space between the second and third reflectors.
- [3] The projection optical system according to claim 2, wherein the position of the fourth reflector satisfies the condition of

where

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d1 is the surface separation between the third and fourth reflectors, and

d2 is the surface separation between the second and third reflectors.

- [4] The projection optical system according to one of claims 1 to 3, wherein absolute values of radii of curvature of all the reflectors fall within the range of 300 mm to 5000 mm.
- [5] The projection optical system according to one of claims 1 to 4, satisfying

400 mm < R3 < 2000 mm

where R3 is the radius of curvature of the third reflector.

[6] The projection optical system according to one of claims 1 to 5, satisfying

0 < R2 < 3000 mm

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where R2 is the radius of curvature of the second reflector.

[7] The projection optical system according to one of claims 1 to 6, satisfying

0 < R6 < 4000 mm

- where R6 is the radius of curvature of the sixth reflector.
 - [8] The projection optical system according to one of claims 1 to 7, wherein the image-side numerical aperture NA is no less than 0.3.
 - [9] An exposure apparatus comprising an illumination system for illuminating a mask set on the first surface, and the projection optical system according to one of claims 1 to 8 for projecting and exposing a pattern of the mask onto a photosensitive substrate set on the second surface.
 - [10] An exposure apparatus according to claim 9, wherein the illumination system includes a light source for supplying an X-ray as exposure light, and projects and exposes the pattern of the mask onto the photosensitive substrate by moving the mask and photosensitive

substrate relative to the projection optical system.